


<b>Search Notes</b>  	<b>Application/Control No.</b>  10599367	<b>Applicant(s)/Patent Under Reexamination</b>  NAGAMUNE ET AL.
	<b>Examiner</b>  STUART W SNYDER	<b>Art Unit</b>  1648

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Dialog: Microorganism, monitor? or detect? or determin?, antibody or antigen, microflow channell, chip	2/3/2009	sws
EAST: Microorganism, monitor? or detect? or determin?, antibody or antigen, microflow channell, chip; inventors	2/3/2009	sws

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--